

Sensors

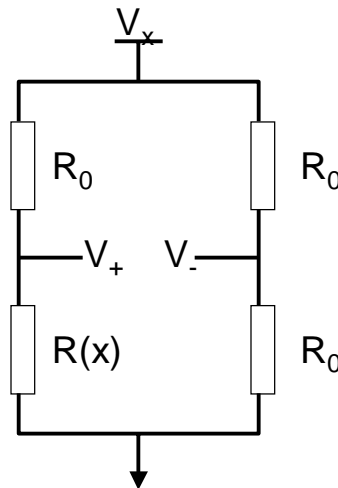
- Resistive, Capacitive
- Strain gauges, piezoresistivity
- Simple XL, pressure sensor
- ADXL50
- Noise

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Resistive sensors

- $R(x) = R_0(1+\alpha x)$
 - E.g. TCR, gauge factor
- Generate thermal noise
- Wheatstone bridge minimizes sensitivity to
 - Nominal resistance value
 - Power supply variation
 - Other inputs
 - $R(x) = R_0(1+\alpha x) (1+\beta y)$

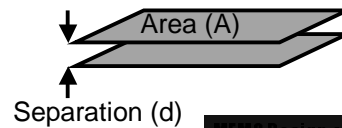


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Capacitive sensors

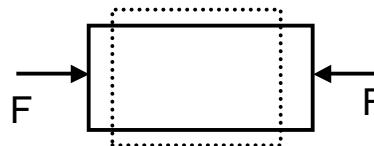
- Typically used to measure displacement
- $C \approx \epsilon_0 A/d$
- Can be used in Wheatstone bridge (with AC excitation)
- Sensitive to environmental coupling
 - Typically want amplifier very close
 - Typically need to shield other varying conductors
 - Definitely don't want charge-trapping dielectrics nearby
- No intrinsic noise



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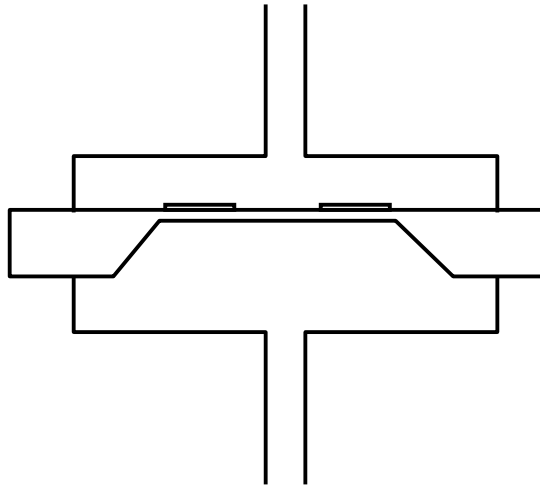
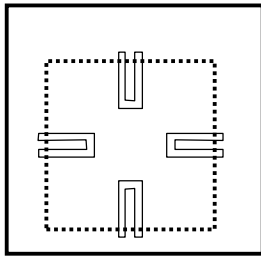
Strain Sensors

- Shape change
 - $\delta L/L = \epsilon$
 - $\delta a/a = -\nu \epsilon$ (Poisson's ratio)
 - $R(a,b,L) = \rho L/A$
 - $R(\epsilon) = R_0(1+(1+2\nu) \epsilon)$
 - $R(\epsilon) = R_0(1+G \epsilon)$
- Piezoresistive
 - $\rho(\epsilon) = \rho_0(1+ G_p \epsilon)$
 - $R(\epsilon) = R_0(1+(G_p+G) \epsilon)$
 - $G_p \sim -20, 30$ (poly), ~ 100 (SCS)
- Piezoelectric
 - Strain generates charge, charge generates strain



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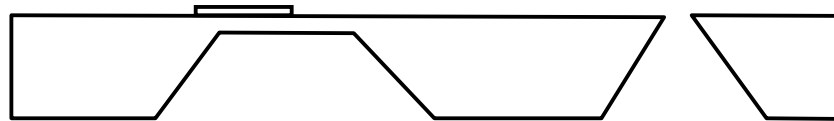
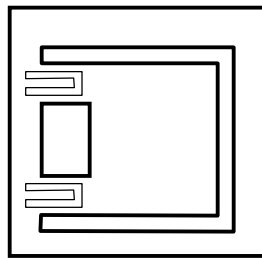
Simple piezoresistive pressure sensor



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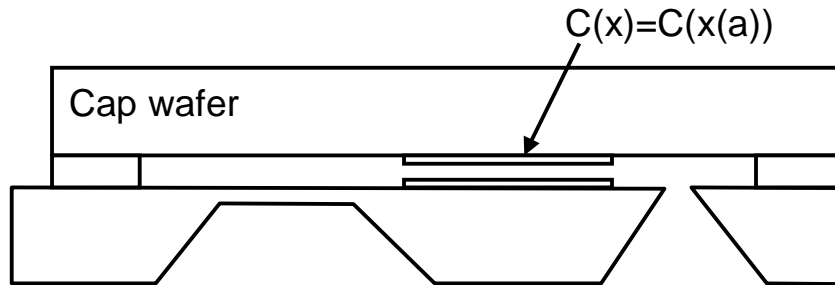
Simple piezoresistive accelerometer



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Simple capacitive accelerometer

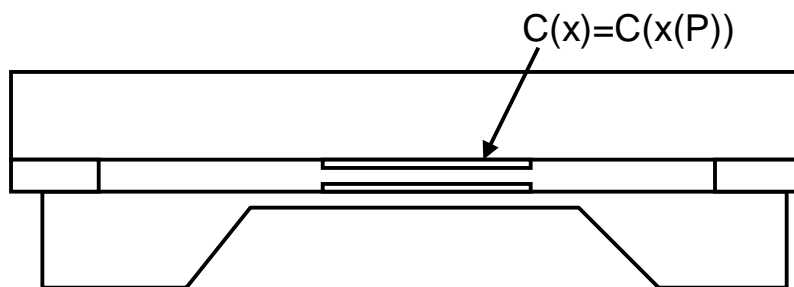


- Cap wafer may be micromachined silicon, pyrex, ...
- Serves as over-range protection, and damping
- Typically would have a bottom cap as well.

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Simple capacitive pressure sensor

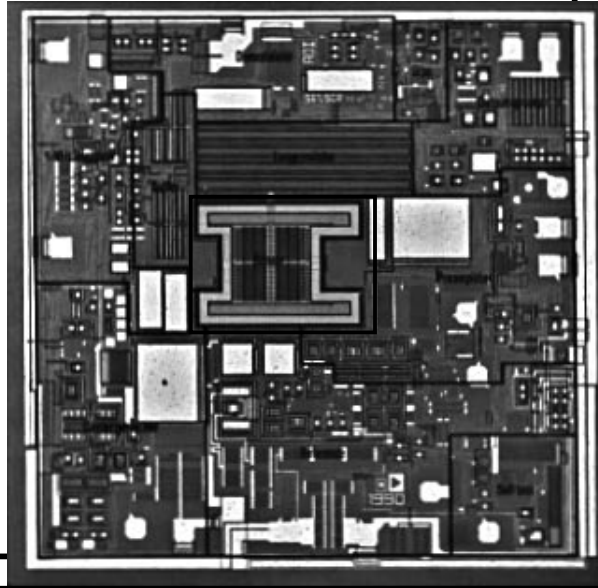


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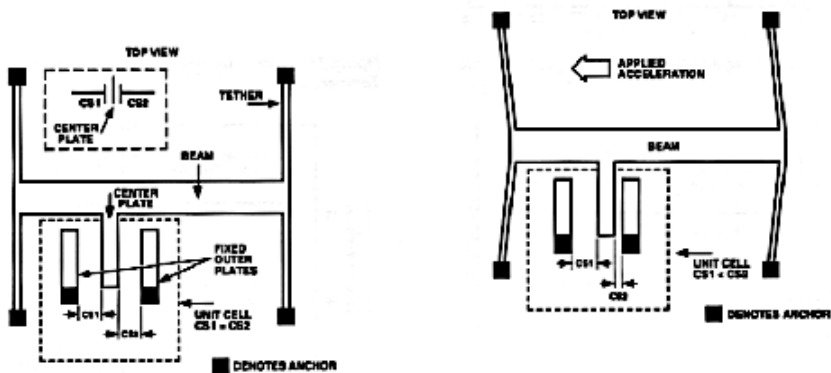
ADXL50 Accelerometer

- $\pm 50g$
- Polysilicon
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BiCMOS
- 3x3mm die



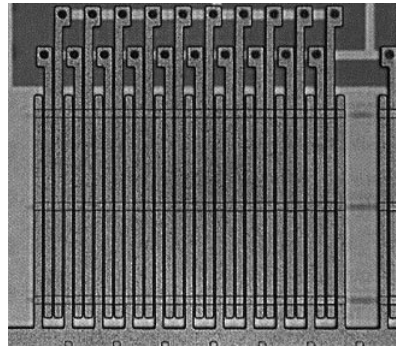
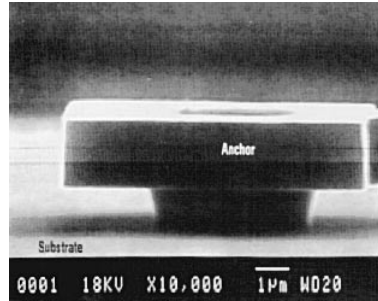
ADXL50 Sensing Mechanism

- Balanced differential capacitor output
- Under acceleration, capacitor plates move changing capacitance and hence output voltage
- On-chip feedback circuit drives on-chip force-feedback to re-center capacitor plates.



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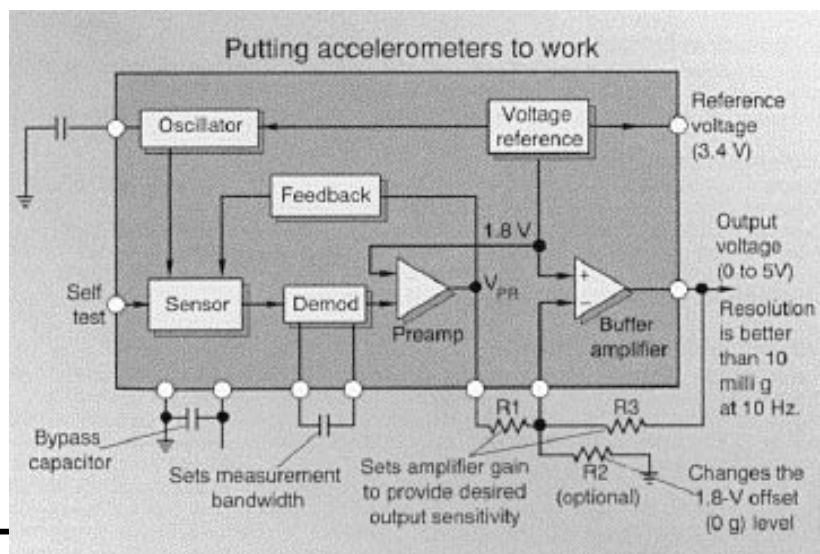
Analog Devices Polysilicon MEMS



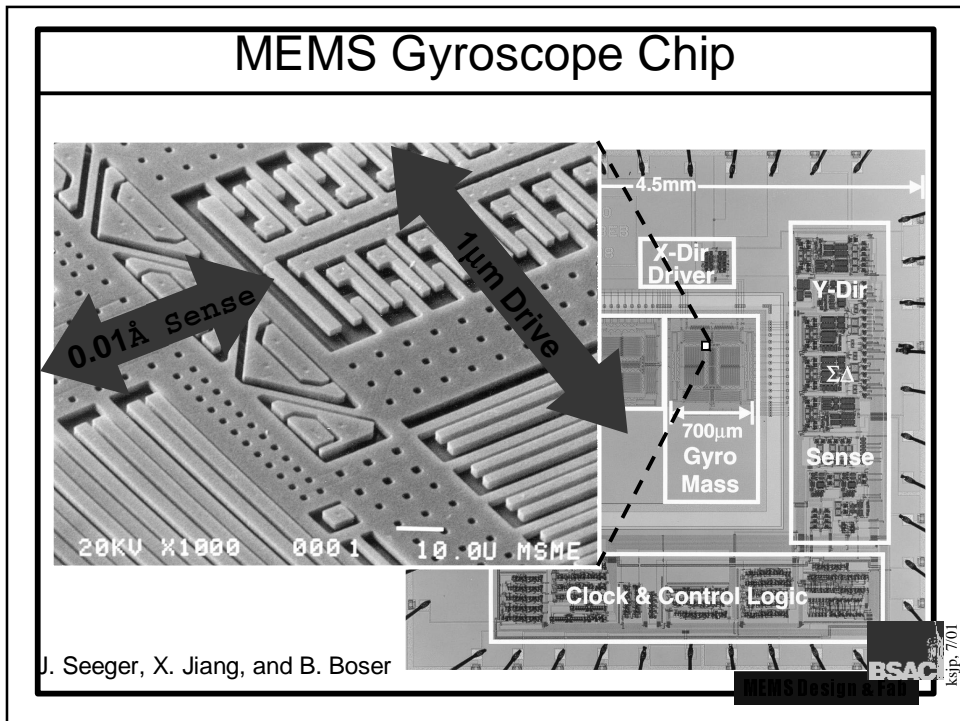
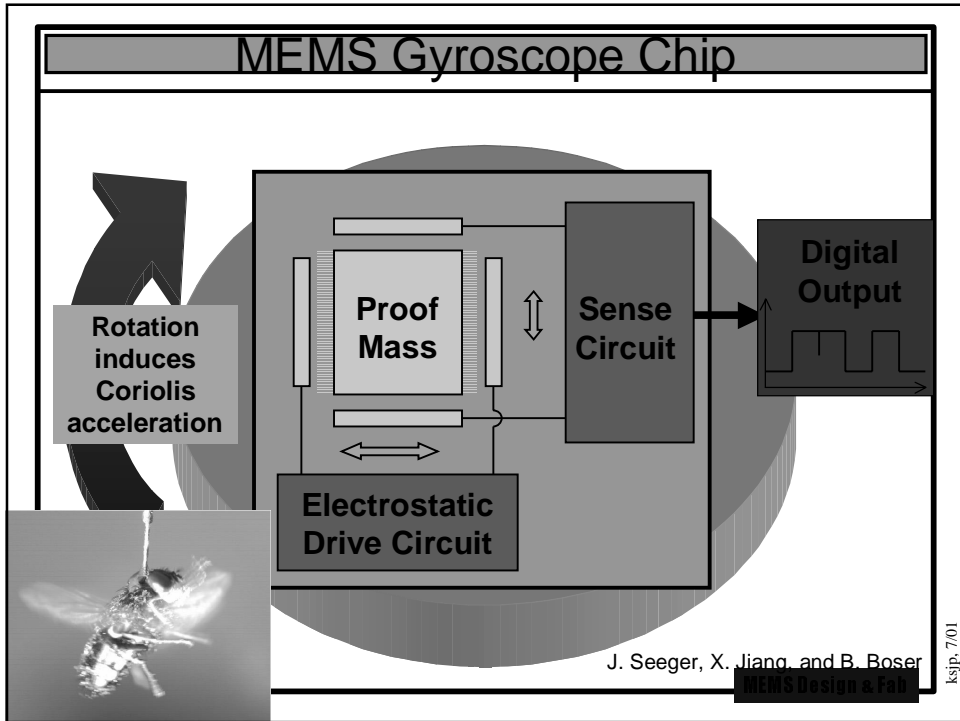
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ADXL50 – block diagram



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Thermal Noise

- Fundamental limitation to sensor performance due to thermal noise
- “White” noise, Johnson noise, Brownian motion all the same
 - Not the same as flicker, popcorn, 1/f noise
- Equipartition theorem (energy perspective)
 - every energy storage mode will have $\frac{1}{2} k_B T$ of energy
- Nyquist (power perspective):
 - Every dissipator will contribute $P_N = 4 k_B T B$
 - B = bandwidth of interest in Hz

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Equipartition

- $\frac{1}{2} k_B T = 4 \times 10^{-21} \text{ J @ room temperature (300K)}$
- $\frac{1}{2} C V^2 = \frac{1}{2} k_B T$
 - $C=1\text{pF} \rightarrow V_n = 60\text{uV}$ (RMS value)
- $\frac{1}{2} k x^2 = \frac{1}{2} k_B T$
 - $K = 1\text{N/m} \rightarrow x_n = 0.06\text{nm}$
- $\frac{1}{2} m v^2 = \frac{1}{2} k_B T$
 - $m = 10^{-9} \text{ kg}$ (~100um cube) $\rightarrow v_n = 2 \times 10^{-6} \text{ m/s}$

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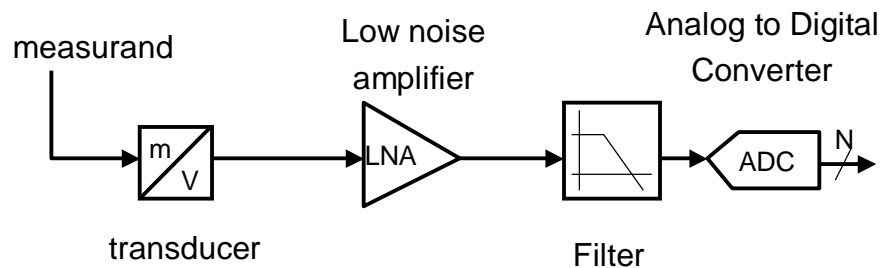
Nyquist

- $P_N = 4 k_B T B$
- In a resistor
 - $P_N = V_N^2/R = 4 k_B T B$
 - $V_N = \text{sqrt}(4 k_B T R B)$
 - $= \text{sqrt}(4 k_B T R) \text{sqrt}(B)$
 - If $R = 1\text{k}\Omega$ then
 - $V_N = 4\text{nV}/\text{sqrt}(\text{Hz}) \text{sqrt}(B)$

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Sensor and interface electronics



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Summary

- Resistive and capacitive sensors most common
- Sensing, amplification, filtering, feedback on the same chip ~\$2
- Minimum detectable signal limited by thermal noise

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